

Application/Control No.	No. Applicant(s)/Patent unde Reexamination	Applicant(s)/Patent under Reexamination	
10/632,665	HAPARNAS ET AL.		
Examiner	Art Unit		
Shin-Hon Chen	2131		

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT, PGPUB, EPO, JPO, DERWENT (BRS search)	7/5/2006	S.C.		